

Deutsche Akkreditierungsstelle GmbH

Entrusted according to Section 8 subsection 1 AkkStelleG in connection with Section 1 subsection 1 AkkStelleGBV

Signatory to the Multilateral Agreements of EA, ILAC and IAF for Mutual Recognition

Accreditation



The Deutsche Akkreditierungsstelle GmbH attests that the calibration laboratory

Mahr GmbH, Standort Esslingen Reutlinger Straße 48, 73728 Esslingen

is competent under the terms of DIN EN ISO/IEC 17025:2018 to carry out calibrations in the following fields:

Dimensional quantities

Length

- Diameter
- Form Error
- Length measuring instruments a)
- Length measuring devices
- Thread

Coordinate measuring technology

Application coordinate measuring machines

The accreditation certificate shall only apply in connection with the notice of accreditation of 04.07.2022 with the accreditation number D-K-15074-02. It comprises the cover sheet, the reverse side of the cover sheet and the following annex with a total of 8 pages.

Registration number of the certificate: D-K-15074-02-00

Berlin,

Dr. Florian Witt

Translation issued:

04.07.2022

Head of Technical Unit

04.07.2022

Head of Technical Unit

The certificate together with the annex reflects the status as indicated by the date of issue.

The current status of any given scope of accreditation can be found in the directory of accredited bodies maintained by Deutsche Akkreditierungsstelle GmbH at https://www.dakks.de/en/accredited-bodies-search.html.

This document is a translation. The definitive version is the original German accreditation certificate.

See notes overleaf.

a) also on-site calibration



Deutsche Akkreditierungsstelle GmbH

Annex to the Accreditation Certificate D-K-15074-02-00 according to DIN EN ISO/IEC 17025:2018

Valid from:

04.07.2022

Date of issue: 04.07.2022

Holder of certificate:

Mahr GmbH, Standort Esslingen Reutlinger Straße 48, 73728 Esslingen

Calibration in the fields:

Dimensional quantities

Length

- Diameter
- Form Error
- Length measuring instruments
- Length measuring devices
- Thread

Coordinate measuring technology

- Application coordinate measuring machines

Within the measurands / calibration items marked with * the calibration laboratory is permitted, without being required to inform and obtain prior approval from DAkkS, to use calibration standards or equivalent calibration procedures listed here with different issue dates.

The calibration laboratory maintains a current list of all calibration standards / equivalent calibration procedures within the flexible scope of accreditation.

The management system requirements of DIN EN ISO/IEC 17025 are written in the language relevant to the operations of calibration laboratories. Laboratories that conform to the requirements of this standard, operate generally in accordance with the principles of DIN EN ISO 9001.

The certificate together with the annex reflects the status as indicated by the date of issue. The current status of any given scope of accreditation can be found in the directory of accredited bodies maintained by Deutsche Akkreditierungsstelle GmbH at https://www.dakks.de/en/accredited-bodies-search.html.

Abbreviations used: see last page

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Permanent Laboratory

Calibration and Measurement Capabilities (CMC)

	Calibrat	.1011	and Me	asurement Capabil	ities (CMC)	
Measurement quantity / Calibration item		Rang	e	Measurement conditions / procedure	Expanded uncertainty of measurement	Remarks
Length Cylindrical setting gauges, Setting ring gauges* Diameter Straightness deviation and Parallelism deviation of surface lines	10 mm	to	250 mm	VDI/VDE/DGQ 2618 Part 4.1:2006	0.3 μm + 5 · 10 ⁻⁶ · <i>d</i> 0.5 μm	d = measured diameter
Roundness deviation				Cut-off wave number = 150	0.1 μm	
Cylindrical setting gauges, Setting ring gauges* Diameter	2mm	to	300 mm	VDI/VDE/DGQ 2618 Part 4.1:2006 Option 3 and 4	1 μm + 5 · 10 ⁻⁶ · <i>d</i>	With coordinate measuring machine
Cylindrical setting gauges, Setting plug gauges* Diameter	1 mm	to	250 mm	VDI/VDE/DGQ 2618 Part 4.1:2006	0.25 μm + 5 · 10 ⁻⁶ · d	d = measured diameter
Straightness deviation and Parallelism deviation of surface lines					0.5 μm	In the area of 1 mm to 3 mm, only Option 3 or
Roundness deviation				Cut-off wave number = 150	0.1 μm	4 with increased measuring uncertainty
Measuring pins* Diameter	0.14 mm	to	0.25 mm	VDI/VDE/DGQ 2618 Part 4.2:2007	0.8 μm	d = measured diameter
	> 0.25 mm	to	0.4 mm		0.6 μm	
	> 0.4 mm	to	3 mm		0.5 μm	
	> 3 mm	to	100 mm		$0.25 \ \mu m + 5 \cdot 10^{-6} \cdot d$	
Straigthness deviation and Parallelism deviation of surface lines	3 mm	to	100 mm		0.5 μm	
Roundness deviation				Cut-off wave number = 150	0.1 μm	
Double sided spherical probe for thread measurement	0.3 mm	to	4 mm	DKS038-EA001:2019-07	0.4 μm	
Roundness deviation		to	40 μm		0.7 μm	
Gap gauges*	0 mm	to	150 mm	VDI/VDE/DGQ 2618 Part 4.7:2005	2 μm + 8 · 10 ⁻⁶ · d	
Straight edges*	0 mm	to		VDI/VDE/DGQ 2618 Part 5.1:2013	1 μm + 5 · 10 ⁻⁶ · <i>l</i>	l = measured length



Permanent Laboratory

Calibration and Measurement Capabilities (CMC)

Measurement quantity	Range			Measurement Capabili	Expanded uncertainty	Remarks
/ Calibration item				conditions / procedure	of measurement	Remarks
Knife straight edges*	0 mm	to	1000 mm	VDI/VDE/DGQ 2618 Part 5.2:2013	1 μm + 5 · 10 ⁻⁶ · <i>l</i>	
Steel squares*	0 mm	to	1000 mm	VDI/VDE/DGQ 2618 Part 7.1:2010	1 μm + 5 · 10 ⁻⁶ · <i>l</i> _z	l_z = leg length
Protractors*	0°	to	360°	VDI/VDE/DGQ 2618 Part 7.2:2008	1′	scale interval ≥ 1'
straightness		to	300 mm		0.5 μm + 5·10 ⁻⁶ l _z	
parallelism					1 μm + 6·10 ⁻⁶ l _z	
Calipers for external, internal and depth dimensions*	0 mm	to	500 mm	VDI/VDE/DGQ 2618 Part 9.1: 2006	15 μm + 15 · 10 ⁻⁶ · <i>l</i>	l = measured length
	> 500 mm	to	1000 mm		15 μm + 20 · 10 ⁻⁶ · <i>l</i>	
Depth calipers*	0 mm	to	1000 mm	VDI/VDE/DGQ 2618 Part 9.2: 2006	20 μm + 20 · 10 ⁻⁶ · <i>l</i>	
Height calipers*	0 mm	to	1000 mm	VDI/VDE/DGQ 2618 Part 9.3:2006	30 μm + 20 · 10 ⁻⁶ · <i>l</i>	
Special calipers	0 mm	to	1000 mm	DKS032-EA001:2019-06	20 μm + 15 · 10 ⁻⁶ · <i>l</i>	
Micrometers*	0 mm	to	200 mm	VDI/VDE/DGQ 2618 Part 10.1: 2001	2 μm + 10 · 10 ⁻⁶ · /	scale interval 1 µm, for higher scale intervals the measurement uncertainty will rise
						200 mm = final value of the measuring range
Reference gauges for micrometers*	25 mm	to	500 mm	VDI/VDE/DGQ 2618 Part 4.4:2009	1 μm + 10 · 10 ⁻⁶ · <i>l</i>	l = measured length
Micrometers with replacable anvils*	0 mm	to	200 mm	VDI/VDE/DGQ 2618 Part 10.2: 2010	3 μm + 10 · 10 ⁻⁶ · <i>l</i>	
Micrometers with dial indicator*	0 mm	to		VDI/VDE/DGQ 2618 Part 10.3:2002	3 μm + 10 · 10 ⁻⁶ · <i>l</i>	
Micrometer heads*	0 mm	to		VDI/VDE/DGQ 2618 Part 10.4:2008		l = measured length
Depth micrometers*	0 mm	to		VDI/VDE/DGQ 2618 Part 10.5:2010	3 μm + 10 · 10 ⁻⁶ · <i>l</i>	=:



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Calibration and Measurement Capabilities (CMC)

Measurement quantity / Calibration item		Range	3	Measurement conditions / procedure	Expanded uncertainty of measurement	Remarks
Internal micrometers with two-point contact*	25 mm	to	500 mm	VDI/VDE/DGQ 2618 Part 10.7:2010	3 μm + 5 · 10 ⁻⁶ · d	d = measured diameter
Internal micrometers with three-line contact*	2 mm	to	100 mm	VDI/VDE/DGQ 2618 Part 10.8:2002	3 μm + 5 · 10 ⁻⁶ · <i>d</i>	100 mm = final value of the measuring range
Dial gauges*		to	100 mm	VDI/VDE/DGQ 2618 Part 11.1:2020 E VDI/VDE/DGQ 2618 Part 11.4:2020	0.8 μm + 12 · 10 ⁻⁶ · <i>l</i>	scale interval ≤ 1 µm, for higher scale intervals the measurement uncertainty will rise
Dial indicators*		to	3 mm	VDI/VDE/DGQ 2618 Part 11.2:2002	0.5 μm	
Lever gauges*		to	1.6 mm	VDI/VDE/DGQ 2618 Part 11.3:2002	0.7 μm	
Indicating snap gauges	0 mm	to	500 mm	DKS029-EA001:2019-05	0.9 μm + 5 · 10 ⁻⁶ · <i>l</i>	I = measuredlengthMeasuring spanof dialindecatorsmax. 5 mm
Lever gauges (quicktests) for external measurement	0 mm	to	200 mm	VDI/VDE/DGQ 2618 Part 12.1:2005	7 μm + 10 · 10 ⁻⁶ · <i>l</i>	l = measured length
Lever gauges (quicktests) for internal measurement*	2 mm	to	200 mm	VDI/VDE/DGQ 2618 Part 13.1:2005	7 μm + 10 · 10 ⁻⁶ · <i>l</i>	
Bore gauges with two- point contact*	1 mm	to	800 mm	VDI/VDE/DGQ 2618 Part 13.2:2005 image 1, image 2, image 3	0.8 μm	Measuring span off 0,1 mm to 3 mm
Inductive probe with measuring device*		to	10 mm	VDI/VDE/DGQ 2818 Part 14.1:2010	0.5 μm	
Inductive probe without measuring device*		to	10 mm		1.2 μm	



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Calibration and Measurement Capabilities (CMC)

	Calibrai	lon	and ivie	asurement Capabil	ities (CMC)	
Measurement quantity / Calibration item		Range	•	Measurement conditions / procedure	Expanded uncertainty of measurement	Remarks
Incremental prope	0 mm	to	100 mm	DKS016-EA001:2017-10	0.35 μm + 12 · 10 ⁻⁶ · <i>l</i>	l = measured length
Snap gauge Thickness gauge	0 mm	to	50 mm	DKS042-EA001:2019-06	7 μm + 10 · 10 ⁻⁶ · <i>l</i>	-
Flat gauge	2 mm	to	100 mm	DKS043-EA001:2019-06	0.5 μm + 5 · 10 ⁻⁶ · <i>l</i>	
Height gauges / Vertical length measuring machines	0 mm	to	1000 mm	VDI/VDE/DGQ 2618 Part 16.1:2009	1.7 μm + 1,2 · 10 ⁻⁶ · <i>l</i>	
Dial gauges- and dial indicator testing devices	0 mm	to	100 mm	DKS044-EA001:2019-06	0.26 μm	Calibration by laser interferometry
	0 mm	to	25 mm	DKS045-EA001:2019-06	0.5 μm + 20 · 10 ⁻⁶ · <i>l</i>	Calibration with incremental probe
Thread gauges (single-start cylindrical ex-ternal and internal threads with straight flanks and symmetrical profile)						
External thread Simple pitch diameter with nominal lead 0,25 mm bis 6 mm	Nomir 3 mm	nal dian	neter 100 mm	VDI/VDE/DGQ 2618 Part 4.8:2006, Option 1	3 μm + 10 · 10 ⁻⁶ · d	d = pitch diameter
Internal thread Simple pitch diameter with nominal lead 0,25 mm bis 6 mm	Nomin 5 mm	al dian	neter 100 mm	VDI/VDE/DGQ 2618 Part 4.9:2006, Option 1	3 μm + 10 · 10 ⁻⁶ · d	



Permanent Laboratory

Calibration and Measurement Capabilities (CMC)

Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement	Remarks
Coordinate measuring technology				
Prismatic, tapered and ball-shaped workpieces		DKS040-EA001:2019-08 Tactile measurements with single point probing with a coordinate measuring machine and determination of regular geometries through geometrical parameters (single-points, straight lines, planes, circles, balls, cylinders, toroids) using the evaluation software of the coordinate measuring machine. Single point measurements in the form of "Self-centering measurements"are not used within the accreditation. For ensuring metrological traceability, the calibration of a similar standard will be realized. Beyond that, following limitations should be considered: -Measuring points have to evenly distributed throughout the form element - at least 50 % of the geometry element's surface has to be covered by measuring points - evaluation of mean	The uncertainty of measurement is determined with a uncertainty measurement balance Part on the basis of the guideline VDI/VDE 2617 part 11:2011. The uncertainty of measurement depends on the measuring task and is specified with a coverage probability of approximately 95 % (coverage factor k=2) Exemplary measurement uncertainty for a described measuring task: Gauge block with a nominal value of 500 mm, using a probe of 150 mm length, determinde is the expanded uncertainty of the inspection feature "distance": U=4.3 mm	For general measuring tasks the measuring uncertainty could be significant differently form the exemplary specified.



On-site Calibration

Calibration and Measurement Capabilities (CMC)

Measurement quantity / Calibration item		Range	9	Measurement conditions / procedure	Expanded uncertainty of measurement 1)	Remarks
Length Calipers for external, internal and depth dimensions*	0 mm	to	500 mm	VDI/VDE/DGQ 2618 Part 9.1:2006	15 μm + 15 · 10 ⁻⁶ · /	l = measured length
	> 500 mm	to	1000 mm		15 μm + 20 · 10 ⁻⁶ · <i>l</i>	1
Depth calipers*	0 mm	to	1000 mm	VDI/VDE/DGQ 2618 Part 9.2:2006	20 μm + 20 · 10 ⁻⁶ · <i>l</i>	
Special calipers	0 mm	to	1000 mm	DKS032-EA001:2019-06	20 μm + 15 · 10 ⁻⁶ · <i>l</i>	
Micrometers*	0 mm	to	200 mm	VDI/VDE/DGQ 2618 Part 10.1:2001	2 μm + 10 · 10 ⁻⁶ · <i>l</i>	scale interval 1 µm, for higher scale intervals the measurement uncertainty will rise 200 mm = final value of the measuring range
_						
Micrometers with replacable anvils*	0 mm	to	200 mm	VDI/VDE/DGQ 2618 Part 10.2: 2010	3 μm + 10 · 10 ⁻⁶ · <i>l</i>	l = measured length
Micrometers with dial ndicator*	0 mm	to	200 mm	VDI/VDE/DGQ 2618 Part 10.3:2002	3 μm + 10 · 10 ⁻⁶ · <i>l</i>	
Depth micrometers*	0 mm	to	300 mm	VDI/VDE/DGQ 2618 Part 10.5:2010	3 μm + 10 · 10 ⁻⁶ · <i>l</i>	
Dial gauges*		to	25 mm	VDI/VDE/DGQ 2618 Part 11.1:2020 E VDI/VDE/DGQ 2618 Part 11.4:2020	3 μm + 12 · 10 ⁻⁶ · <i>l</i>	
Dial indicators*		to	3 mm	VDI/VDE/DGQ 2618 Part 11.2:2002	0.5 μm	
ever gauges*		to	1.6 mm	VDI/VDE/DGQ 2618 Part 11.3:2002	0.7 μm	
ndicating snap gauges	0 mm	to	500 mm	DKS029-EA001:2019-05	0.9 μm + 5 · 10 ⁻⁶ · <i>l</i>	l = measured length Measuring span of dial indecators max. 5 mm
ever gauges (quicktests) or external measurement	0 mm	to	200 mm	VDI/VDE/DGQ 2618 Part 12.1:2005	8	l = measured length
Snap gauge Thickness gauge	0 mm	to	50 mm	DKS042-EA001:2019-06	7 μm + 10 · 10 ⁻⁶ · <i>l</i>	and the second s



Abbreviations used:

CMC Calibration and measurement capabilities (Kalibrier- und Messmöglichkeiten)

DIN Deutsches Institut für Normung e.V.

VDE Verband der Elektrotechnik, Elektronik und Informationstechnik e.V.

VDI Verein Deutscher Ingenieure e.V. DGQ Deutsche Gesellschaft für Qualität

DKS Calibration instruction of the Mahr GmbH, location Esslingen